

Performance Characteristics

- ✧ Frequency range :35GHz~60GHz
- ✧ Small signal gain :20dB
- ✧ Saturated output power :36dBm
- ✧ DC power supply : Vd=18V@Id=820mA(Vg=-1.5V)
- ✧ Chip size : 3.80 mmx2.38 mmx0.05 mm

Product Introduction

A broadband power amplifier chip covering the Q-band and U-band, with a frequency range of 35GHz~60GHz, a typical small signal gain of 20dB, a typical saturated output power of 36dBm, and a typical additional efficiency of 13%.

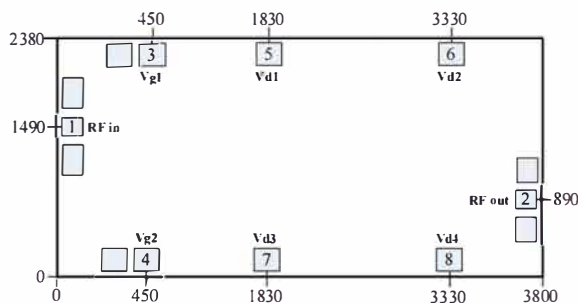
Electrical Performance Table (Vd= 18V,Id=820mA,TA=+25°C)

Parameter	Min	Typ	Max	Unit
Frequency Range	35		60	GHz
Small Signal Gain		20		dB
Gain Flatness		±3		dB
Saturated Output Power		36		dBm
Power Added Efficiency		13		%
Power Gain		11		dB
Input Standing Wave		1.4		-
Output VSWR		1.4		-
Saturation Current		1700		mA

Use Restriction Parameters

Negative Gate Voltage	-5V
Positive Drain Voltage	20V
Input Power	32dBm
Storage Temperature	-65°C~150°C
Usage Temperature	-55°C~85°C

External Dimensions



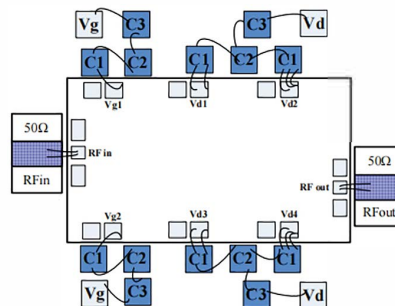
Notes:

- 1) All dimensions marked are in micrometers (μm);
- 2) Dimensional tolerance for external dimensions: ±50μm;
- 3) The chip thickness is 50μm.

Definition Of Bonding Pressure Point

Number	Symbol	Function Description	Size(μm ²)
1	RFin	RF signal input terminal, external 50 ohm system, no need for DC isolation capacitor	80×80
2	RFout	RF signal output terminal, external 50 ohm system, no need for DC isolation capacitor	80×80
3、4	Vg1、Vg2	Gate voltage feeding terminal requires external 100pF, 10000pF, and 10uF bypass capacitors	100×100
5、6、7、8	Vd1、Vd2、Vd3、Vd4	The drain voltage feeding terminal requires external 100pF, 10000pF, and 10uF bypass capacitors	140×140

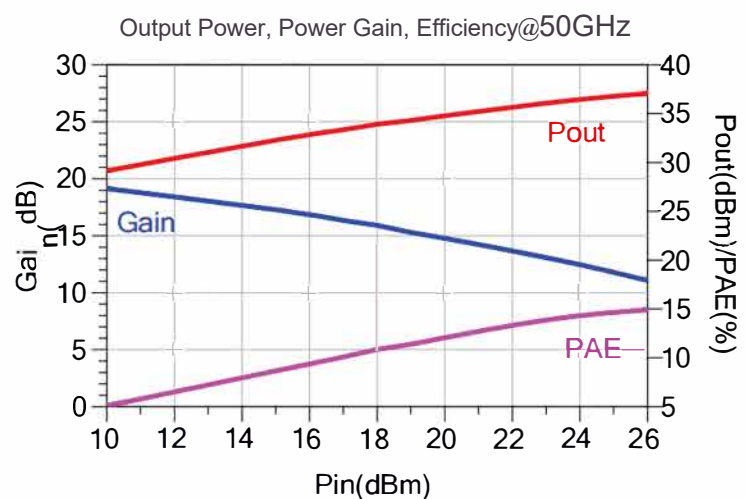
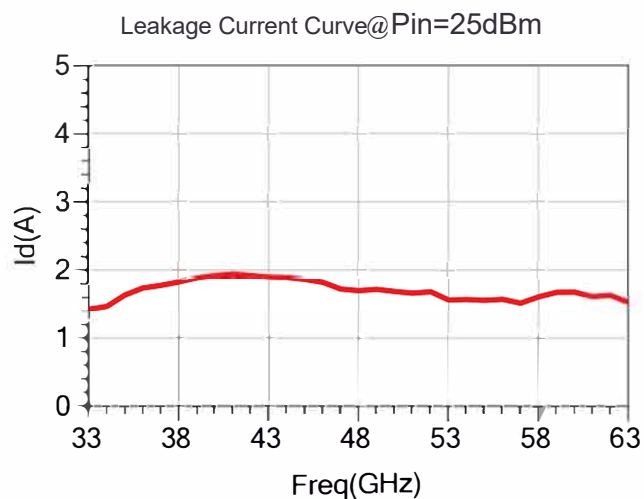
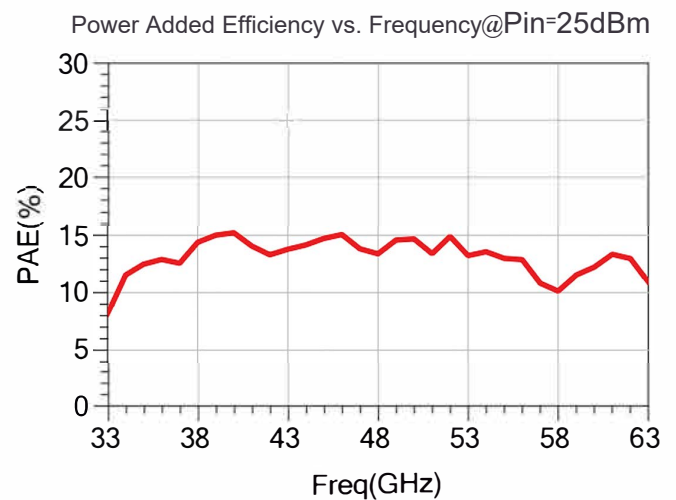
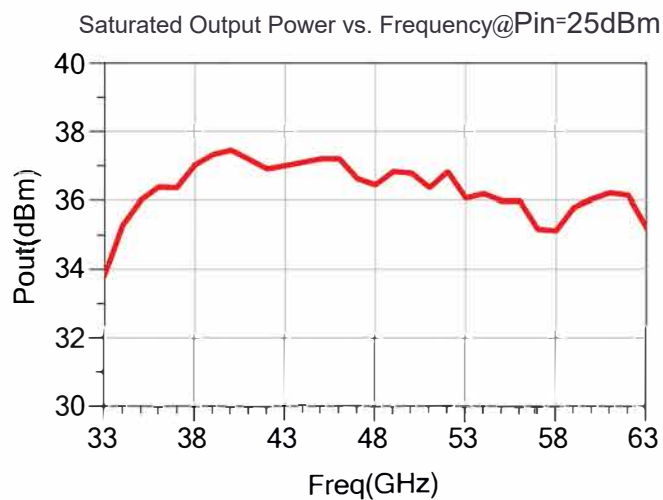
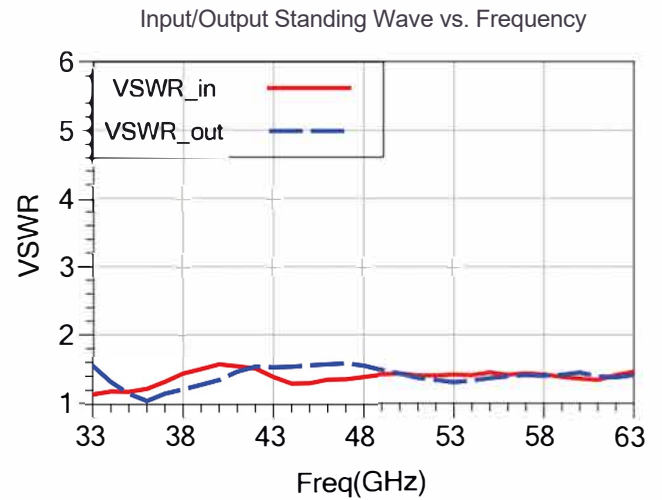
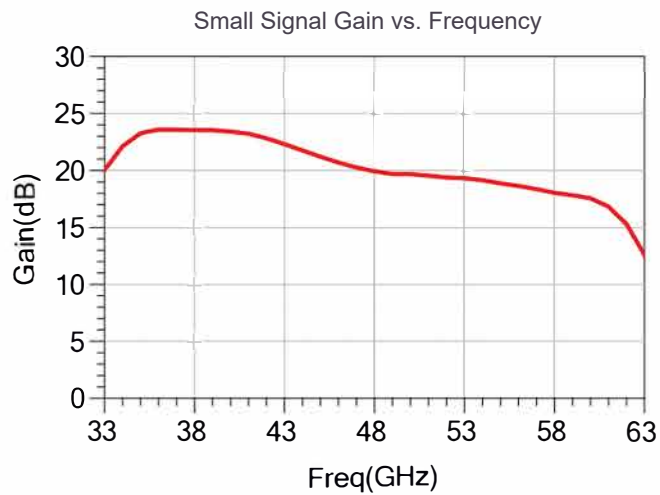
Suggested Assembly Diagram



Notes:

The capacitance of the peripheral capacitor C1 is 100 pF, the capacitance of C2 is 10000 pF, and the capacitance of C3 is 10 μf. It is recommended to use a single-layer capacitor for C1 and try to be as close to the chip bonding point as possible.

On Chip Pulse Test Curve ($T_A = +25^\circ\text{C}$) $V_d = 18\text{V}$, $I_d = 820\text{mA}$



Note:

- 1)Storage: The chip must be placed in a container with electrostatic protection and stored in a nitrogen environment.
 - 2)Cleaning treatment: Bare chips must be operated and used in a purified environment, and it is prohibited to use liquid cleaning agents to clean the chips.
 - 3)Electrostatic protection: Please strictly comply with ESD protection requirements to avoid electrostatic damage.
 - 4)Conventional operation: To retrieve the chip, please use a vacuum chuck or a precision pointed camera. During the operation, avoid touching the chip surface with tools or fingers.
 - 5)Power on sequence: When powering on, apply gate voltage first, then drain voltage; When powering off, first remove the leakage voltage, then remove the gate voltage.
 - 6)Mounting operation: Chip installation can use AuSn solder eutectic sintering or conductive adhesive bonding process. The mounting surface must be clean and flat, and the gap between the chip and the input/output RF connection substrate should be minimized as much as possible.
Sintering process: Use 80/20 AuSn for sintering, with a sintering temperature not exceeding 300 °C, a sintering time as short as possible, not exceeding 20 seconds, and a friction time not exceeding 3 seconds.
Adhesive process: When bonding conductive adhesive, try to minimize the amount of glue applied, and refer to the information provided by the conductive adhesive manufacturer for curing conditions.
 - 7)Bonding operation:
Unless otherwise specified, use 2 bonding wires (25 μ m diameter gold wire) for RF input and output, and keep the bonding wires as short as possible.
Hot ultrasonic bonding temperature is 150 °C, using the smallest possible ultrasonic energy.
 - 8)Please contact the supplier if you have any questions.
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